Compact pulsed laser deposition system for in-situ polarized neutron reflectometry Grigorii Kirichuk^a, Alexey Grunin^a, Artur Dolgoborodov^b, Pavel Prokopovich^a, Petr Shvets^a, Alexey Vorobiev^c, Anton Devishvilli^d, Alexandr Goikhman^b, Ksenia Maksimova^b ^aResearch and Educational Center "Functional Nanomaterials", Immanuel Kant Baltic Federal University, 236041, Kaliningrad, Russian Federation ^bKoenigssystems UG, 22869, Schenefeld bei Hamburg, Germany. ^cNanoLund and Physical Chemistry, Lund University, PO Box 124, 22 100Lund, Sweden ^dInstitut Laue-Langevin, 71 avenue des Martyrs, 38000 Grenoble, France

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<u>Abstract</u>

The development of ferromagnet/heavy metal thin-film structures, such as CoFeB/Mo, with spin-orbit interaction requires advanced methods for their production and study. Polarized neutron reflectometry (PNR) provides unique insights into the evolution of magnetic properties, especially when applied *in-situ* during the growth process. Pulsed laser deposition (PLD) is a versatile method for producing magnetic thin films, and combining PLD with *in-situ* PNR measurements offers new possibilities for their investigation.

In this work, we developed a compact vacuum chamber integrated into the neutron instrument, enabling step-by-step deposition and *in-situ* PNR measurements. A multilayer Mo/[CoFeB/Mo]₁₂ structure was grown, and neutron reflectivity curves measured after each cycle revealed the gradual evolution of sample properties. A weak magnetic field response suggested the potential formation of perpendicular magnetic anisotropy (PMA) at CoFeB/Mo interfaces. Additionally, a single CoFeB film was annealed up to 450°C, followed by the deposition of a \sim 5 Å Mo layer. PNR measurements in magnetic fields of 0.01 T and 0.75 T showed a significant increase in in-plane magnetization, confirming PMA formation.

Thus, we demonstrate the first successful operation of a combined PLD and *in-situ* PNR system, showcasing its capabilities for characterizing single-layer CoFeB and multilayer CoFeB/Mo thin-film structures.

Introduction

Spin-orbit coupling at the ferromagnetic/heavy metal (FM/HM) interface plays an essential role in spintronic devices contributing to such phenomena as perpendicular magnetic anisotropy, spin-orbit torque, magnetic damping, tunnel magnetoresistance, or Dzyaloshinskii-Moriya

interaction [1-5]. Studying these effects requires the development of ultrathin metal films (~5-20 Å) that imposes many difficulties and limitations [2,3,6]. For example, it is almost impossible to determine layer-by-layer magnetic characteristics and the evolution of the magnetic structure during the growth process.

Magnetic thin-film structures can be investigated using the magneto-optical Kerr effect (MOKE). This technique, implemented into the growth setup, allows for conducting in-situ measurements [7-9]. However, using in-situ MOKE is challenging to study multilayer thin-film structures with complex magnetic ordering [10,11]. In multilayer structures, the effect of each magnetic layer combines with the effects of the subsequent layers, which makes processing and interpretation of data difficult [12]. Also, the orientation of magnetic domains or anisotropy within each layer imposes further limitations on the measurement process and the analysis of the obtained results [13]. Additional difficulties may arise due to thickness fluctuations and roughness at the interfaces between the layers. The only method that allows the investigation of such samples is polarized neutron reflectometry (PNR) [14, 15].

One of the key advantages of PNR is its ability to perform layer-by-layer studies of the magnetic properties of thin-film structures, providing detailed information about the magnetic moment and its orientation, as well as the thickness, density, and roughness of each layer. This makes neutron reflectometry a versatile and powerful tool for investigating thin magnetic films [16–18]. However, integrating growth setups into the research complex for *in-situ* experiments remains challenging due to the complexity of the equipment. While systems such as magnetron sputtering and molecular beam epitaxy have been successfully implemented for *in-situ* studies [19–21], these are relatively cumbersome solutions that require complex installation, adjustment, and a non-trivial integration process into the neutron setup.

A possible solution to these problems is to use a separate small vacuum transfer chamber (case): the sample is placed in the chamber after the growth process, and then the chamber is installed in the gap between the magnets of the neutron beamline at the Large Scale Facility [22].

Pulsed Laser Deposition offers significant advantages for such applications. In PLD setups, only the target and sample are located inside the vacuum chamber, while all key components, including the laser and optical path, remain outside [23]. This design allows for flexible geometric positioning around the chamber, facilitating integration into the beamline. PLD also enables the use of small targets (a few millimeters in size), optimizing resource usage. Additionally, the high kinetic energy of particles generated in PLD allows for the creation of a wide range of thin-film structures, including metastable phases [24-28]. Importantly, growth recipes developed on standard laboratory PLD systems can be easily transferred to compact versions, ensuring reproducibility and efficiency during experiments.

In our work, we present an advanced approach to the problem of conducting in-situ PNR measurements during the sample growth. We developed a vacuum chamber for pulsed laser deposition, which is placed in the gap between the magnets used to create an external magnetic field. In this case, it becomes possible to grow ultrathin metal films in a high vacuum and study them by neutron reflectometry at the same time, without moving the sample. A gas inlet with a precise mass-flow controller and a resistive heater incorporated in the sample holder make it possible to study the magnetic properties of the growing structures depending on the temperature and vacuum conditions.

As an example, we sequentially grew a Mo/[CoFeB/Mo]₁₂ multilayer structure and measured the neutron reflectivity at each growth stage. Our measurements demonstrate the potential for forming perpendicular magnetic anisotropy (PMA) in such multilayer systems. We also studied the properties of a single CoFeB film before and after annealing at 450 °C. Following the annealing, a 5 Å layer of molybdenum was deposited on top of the film, which induced the formation of PMA in the bilayer system of CoFeB/Mo.

Technical Description

1. Overview of main features

Our compact PLD system is designed for use at the SuperADAM station, Institut Laue-Langevin (ILL), Grenoble, France [29] (Fig. 1a). The chamber dimensions and form factor allow installing it in the gap between the magnets. Such positioning makes it possible to grow thin-film structures and immediately investigate them by PNR inside the same vacuum volume. Nd:YAG pulsed laser guided by the optical system is used for the deposition. The schematic of our PLD facility with the labeling of key components is given in Fig. 1b. Main features of our system are:

• The PLD process enables the deposition of a wide range of thin-film materials with varying complexity.

• The sample size is up to 20x20 mm², which is optimal for gathering high-quality data from neutron reflectometry.

• The base chamber pressure is 10^{-6} Pa, which is sufficient for the growth of pure metal thin films.

• A resistive heater is mounted under the sample, and it allows temperatures of up to 800 °C to be reached.

• Motorized sample rotation allows for achieving maximal film uniformity over the entire sample area along with the heating of the sample.

• Target-sample distance is variable within the working stroke of 50 mm.

• Video CCD cameras allow monitoring of the sample and the target for precise remote control of the experiment.

• A closed optical case protects against laser radiation leakage into the experimental area.

• A gas inlet with precise mass-flow controllers allows working in an atmosphere of oxygen, argon, nitrogen, etc., which expands the range of deposited materials.

• Several different targets can be installed on the target holder to deposit multi-component structures.

• The low weight (16 kg) and small size of the chamber make its installation and maintenance simple and fast.



Fig. 1. a) Photograph of the PLD system installed in the gap between the magnets of the SuperADAM station, ILL. b) Schematic of the PLD facility.

2. Internal design

Inside the vacuum chamber of our PLD system, there are several components, including sample and target holders, sample shutter, several windows, gas inlet, and power connector (Fig. 2). The main part of the internal construction is the sample unit (Fig. 3). The unit is designed to hold a substrate of up to 20x20 mm². The substrate is attached to a replaceable holder, which makes sample changing quick and simple. The substrate is heated by a graphite heater, which can be used to achieve temperatures of up to 800 °C. A thermocouple built into the sample unit allows for a high-precision measurement of the substrate temperature. For the heating system, there is a power feedthrough with a type-K thermocouple connector mounted on the chamber via a DN16CF flange. The heating and temperature measurements can be done simultaneously with sample rotation during the deposition. All wires are electrically insulated by ceramic beads. Ceramic

insulation around the heater and the external molybdenum shield serves as thermal insulators to protect the cover and base of the PLD chamber from overheating.



Fig. 2. A photograph of the internal design of the PLD chamber. Here, the sample unit is in a fixed position due to the requirement of the conducted experiment.

The entire sample unit is made of titanium. This material was chosen to avoid any possible influence of the applied external magnetic field on the position of the sample. The sample shutter is also made of titanium. It can be used to tightly close the sample during laser beam alignment or target cleaning to avoid unwanted deposition processes.

The sample unit with the bracket is attached to the chamber via a linear actuator on a corrugated pipe on a DN16CF flange. Linear displacement allows changing the target-sample distance (the total linear stroke is 50 mm). For neutron reflectometry measurements, the sample should be in the center of the electromagnets. This position coincides with the center of the PLD chamber. In this position, the target-sample distance is 70 mm. Also, the sample unit is motorized to rotate the substrate. The rotation speed can be varied from 0.1 to 50 rpm. Motorized rotation is used for the precise positioning of the sample for neutron measurements and for achieving the uniform deposition of thin films.



Fig. 3. Schematic of the sample unit of the PLD system.

When the sample is in the center of the chamber (and, accordingly, in the center of the magnets), the maximum achievable angle of incidence and reflection of the neutron beam is 11° $(Q_z \sim 0.23 \text{ Å}^{-1})$ (Fig. 4a). This angle can be increased to 20° $(Q_z \sim 0.42 \text{ Å}^{-1})$ if the sample is shifted by 26 mm down from the center (Fig. 4b). Such range of angles is sufficient to obtain high-quality data from neutron measurements.



Fig. 4. Ranges of maximum angles of incidence and reflection for the sample position: a) at the center of the chamber/magnets, b) shifted by 26 mm.

Experimental details

The scheme of the experiment for measuring polarized neutron reflectometry for a sample grown in the PLD chamber installed directly in the magnet system at the SuperADAM station is given in Fig. 5. A monochromatic neutron beam with a wavelength of $\lambda = 5.21$ Å and polarization $P_0 = 99.8\%$ was used for the measurements. From the neutron guide, the beam goes through the monochromator, polarizer, and spin flipper and then hits the sample located in the PLD chamber. The beam goes in and out of the chamber through aluminum neutron windows. A more detailed description of the measuring station and the principles of the PNR method can be found in

references [29, 30] and [14, 15, 31], respectively. Neutron reflectometry data were collected in magnetic fields of 0.01, 0.1 and 0.75 T. The fitting of the collected data was carried out using the open-source GenX software [32].



Fig. 5. Scheme of the in-situ PNR experiment. Film growth and reflectometry measurements are done in the PLD chamber installed in the gap between the magnets.

For the deposition, we utilized a Nd:YAG laser equipped with harmonic splitters to emit radiation at a wavelength of 266 nm. The laser beam scanned the target using a motorized mirror. The beam was focused on the target into a spot with a diameter of 1 mm. The target-sample distance and the sample rotation speed were 70 mm and 10 rpm, respectively. The laser pulse energy, the pulse repetition rate, and the duration of each pulse were 30 mJ, 10 Hz, and 7 ns, respectively. Thin films were deposited from stoichiometric targets of the corresponding materials: CoFeB from a $Co_{40}Fe_{40}B_{20}$ target (target purity 99.99%) and molybdenum from a Mo target (purity 99.99%). All thin-film structures were grown at room temperature in a high vacuum (base pressure $- 1x10^{-6}$ Pa). Two types of substrates were used for the deposition: (100)-oriented single-crystal silicon with natural oxide (oxide thickness ~ 2.5 nm) and (100)-oriented single-crystal silicon with thermal oxide (oxide thickness ~ 750 nm).

The thickness and chemical composition of produced films were determined using Rutherford backscattering spectrometry (RBS). RBS was done at the Van de Graaff accelerator AN2500 (High Voltage Engineering Europa B.V.) with energy of the incident ⁴He⁺ beam of 1.4 MeV. The angle between the incident beam and the normal to the surface of the sample was 5°, and the scattering and exit angles were 160° and 20°, respectively. The experimental RBS spectra were fitted using Rump software [33].

Experimental Results

1. Uniformity of thin films

To obtain high-quality and relevant data from neutron reflectometry, it is necessary to achieve uniformity in the thickness of the grown films across the entire area of the sample. Also, precise thickness control is important for certain applications. For instance, the thickness of the CoFeB film is a critical parameter that determines the magnetic properties (the formation of PMA) of a CoFeB/Mo bilayer.

For calibration purposes, we produced a CoFeB/Mo film with an approximate thickness of each layer of 20 Å. The sample was grown on a single-crystal silicon substrate (20x20 mm²) without thermal oxide. The thickness of the film was measured in several points of the sample by RBS (Fig. 6). The maximum thickness variation for a single layer is 1 Å (Fig. 6a and Fig. 6b), while it is 2 Å for a bilayer structure (Fig. 6c). Although a gradient from the edge to the center is still present, such uniformity is considered as a suitable result for further research.



Fig. 6. Diagrams of the thickness distribution for the CoFeB/Mo bilayer: a) CoFeB layer, b) Mo layer, c) total thickness. d) RBS spectrum of the film (blue dotted line is experimental data, red line is simulated data).

2. Multilayer structure

For PNR studies, a multilayer structure Mo/[CoFeB/Mo]₁₂ was grown step-by-step on a single-crystal silicon substrate with thermal oxide. After each deposition step, we interrupted the growth and performed reflectivity measurements:

• 1st step – growth of Mo/CoFeB/Mo structure (designated as ML1)

- 2nd step development of ML1 to Mo/[CoFeB/Mo]₄ structure (designated as ML4)
- 3rd step development of ML4 to Mo/[CoFeB/Mo]₈ structure (designated as ML8)
- 4th step development of ML8 to Mo/[CoFeB/Mo]₁₂ structure (designated as ML12)

Neutron reflectometry measurements of the components R⁺ and R⁻ were conducted in a magnetic field of 0.1 T, oriented in the plane of the sample. The measurement results, along with data modeling for each cycle, are presented in Fig. 7a, which clearly shows the evolution of the structure complexity after each deposition step. Observation of distinct Kissing oscillations confirms high repeatability of the thicknesses of individual layers during different growth cycles. After the fitting of the experimental results (see Figure 7b for simulated SLD profiles of ML12 structure), we obtained thickness and density of each layer. For CoFeB layers, the thickness and nSLD were 8 ± 1 Å and $(5.6 \pm 0.6) \times 10^{-6}$ Å⁻², respectively. For molybdenum layers, the corresponding parameters were 58.0 ± 1.5 Å and $(4.64 \pm 0.15) \times 10^{-6}$ Å⁻². Magnetic density of CoFeB layers was determined from the magnetic SLD profile (mSLD) yielding $(0.03 \pm 0.01) \times 10^{-6}$ Å⁻². The obtained value corresponds to the magnetization of 9 ± 3 kA/m.



Fig. 7. a) PNR curves for R⁺ and R⁻ polarizations for each deposition step (for clarity, the curves are offset from their original position). The dotted lines represent the measured data, while the solid lines are the modeled curves. b) Nuclear and magnetic SLD (nSLD and mSLD respectively) profiles for the final structure ML12; z = 0 is the interface between the substrate and the multilayer film (for clarity, the mSLD profile values are multiplied by 10).

The magnetization of the CoFeB film is significantly lower compared to the values typically observed in ultrathin films [34]. It is worth noting that no visible splitting between R⁺ and R⁻ curves is observed, regardless of the number of layers. Previously, the magnetic properties of similar multilayer structures with thin ferromagnetic films were investigated [35]. Moreover, neutron reflectometry of [Ru/CoFeB(8Å)/Pt]₁₀ structure revealed the presence of PMA [17]. Finally, PMA in ferromagnetic CoFeB was studied by PNR [36, 37]. All these works demonstrate that the absence of splitting between R⁺ and R⁻ curves at low magnetic fields serves as a primary

indicator of the presence of PMA. Based on these findings, we suggest that one of the main reasons for the weak in-plane magnetization of the CoFeB film is the formation of PMA within the CoFeB/Mo structure. Interestingly, in our samples magnetic anisotropy is formed in a non-annealed structure.

The results of this experiment can contribute to a deeper understanding of the origin of PMA in multilayer structures. However, further studies are required to explore this effect in more detail.

3. PMA in CoFeB/Mo

To investigate the dependence of the magnetic properties on temperature, we produced a single-layer CoFeB film $(15 \pm 2 \text{ Å})$ on a single-crystal silicon substrate with thermal oxide. We conducted a stepwise annealing of the film by gradually increasing the temperature from 100°C to 450°C over a period of 1.5 hours. Neutron reflectivity measurements were performed both before annealing and after the sample cooling to room temperature in a magnetic field of 0.01 T. After the fitting of the experimental curves (Fig. 8a), we obtained nSLD and mSLD profiles (Figs. 8c and 8d). The profiles demonstrated that thermal annealing led to the diffusion of boron into the SiO₂ substrate, resulting in an increase of the density of the CoFeB film. Consequently, an interfacial mixing layer of SiO₂-B was formed in the near-surface region of the substrate (labeled as "mix" in the figures). The thickness, density and magnetic properties of the film before and after annealing are summarized in Table 1.



Fig. 8. a) PNR curves for the CoFeB film before and after annealing. b) Schematic representation of the structural changes in the film after the annealing. c) and d) nSLD and mSLD profiles for the film before and after annealing, respectively.

State	Layer	Thickness (Å)	nSLD *10 ⁻⁶ (Å ⁻²)	mSLD *10 ⁻⁶ (Å ⁻²)	Magnetization (kA/m)
Non- annealed	CoFeB	15.0 ± 2.0	5.72 ± 0.11	1.7 ± 0.2	640 ± 90
Annealed	Mix (SiO ₂ -B)	7.0 ± 1.0	5.4 ± 0.3	_	_
	CoFeB	15.0 ± 2.0	6.0 ± 0.3	2.0 ± 0.15	760 ± 60

Table 1. Fitting results of the PNR curves of the CoFeB film before and after annealing.

The diffusion of boron from CoFeB films (including the diffusion into the SiO₂ substrate [39]) was demonstrated previously [39, 40]. One of the potential consequences of boron migration from CoFeB is the formation of a magnetic dead layer (MDL), which can negatively affect the magnetic properties of the structure. However, in our case, we observed the increasing of magnetization value. The possible explanation of this effect is the formation of individual CoFe crystallites [41], which possess a higher specific magnetization and could compensate for the formation of the

MDL. Nevertheless, investigating of such subtle effects is a challenging task that requires a more comprehensive approach and further experimental studies.

To investigate the formation of PMA, we deposited a molybdenum layer (approximately 5 Å) on the annealed CoFeB film. The resulting structure was not annealed additionally. After the deposition, two neutron reflectivity measurements were performed under magnetic fields of 0.01 T and 0.75 T. The reflectivity curves for both measurements are shown in Fig. 9a, while the corresponding nSLD and mSLD profiles are presented in Fig. 9b. The thickness of the molybdenum layer was determined to be 5 ± 1 Å, with an nSLD value of $(4.6 \pm 0.4) \times 10^{-6}$ Å⁻².



Fig. 9. a) PNR curves for the CoFeB/Mo sample measured under magnetic fields of 0.01 and 0.75 T. b) nSLD and mSLD profiles for the CoFeB/Mo sample (mSLD is shown for measurements taken at 0.01 and 0.75 T).

We can see a significant difference between the magnetic properties of the structure at weak and strong magnetic fields. Specifically, for a field of 0.01 T, the mSLD of CoFeB was $(0.58 \pm 0.12)x10^{-6}$ Å⁻², while at 0.75 T, it increased to $(1.5 \pm 0.15)x10^{-6}$ Å⁻² (corresponding to magnetizations of 210 ± 40 and 550 ± 50 kA/m, respectively). Similarly to our previous study on multilayer structures and the findings reported in literature [18, 38], we conclude that perpendicular magnetic anisotropy is formed in our bilayer CoFeB/Mo structure.

The investigation of PMA in our sample is of interest for two main reasons. First, despite on the partial degradation of the CoFeB layer during the annealing process, we could still obtain the magnetic anisotropy. This observation could be crucial for a deeper understanding of the mechanisms behind PMA formation and the factors influencing it. Second, perpendicular magnetization is observed even with an ultrathin (5 Å) molybdenum capping layer. Achieving this result was possible by using the unique combination of neutron reflectometry and pulsed laser deposition techniques. However, further in-depth analysis and additional studies are required to fully understand the observed phenomena.

<u>Summary</u>

We designed and constructed a vacuum chamber for pulsed laser deposition and in-situ measurements by polarized neutron reflectometry. Our PLD facility was customized for the SuperADAM station, ILL. The chamber was installed in the gap between the magnets, making it possible to grow thin-film structures and immediately investigate them by PNR. The specially designed sample holder is capable of rotating the 20x20 mm² substrate to achieve maximum uniformity of thin films and is equipped with a graphite heater for annealing substrates and samples. The PLD method can be used to produce both single-layer films and multilayer structures with high repeatability and outstanding magnetic properties. In our work, we showed several examples of sample growth and in-situ characterization. We produced a multilayer structure Mo/[CoFeB/Mo]₁₂ in several steps. After each growth step, we measured PNR curves and observed the evolution of the structure. These measurements demonstrated the potential for forming of the PMA at the CoFeB/Mo interfaces. The low value of the in-plane magnetization (9 kA/m) might indicate the high quality of the obtained anisotropy. To further study PMA, we conducted an analysis of the magnetic properties of a bilayer structure CoFeB(15Å) / Mo(5Å). First, we deposited a CoFeB film and annealed it at temperatures of up to 450 °C. After the annealing, a mixing layer of SiO₂-B (approximately 7 Å) was formed at the interface with the substrate; however, the magnetization increased from 640 to 760 kA/m. After that, we deposited a thin molybdenum layer (5 Å) and demonstrated the formation of PMA in the bilayer structure by neutron reflectivity. The in-plane magnetization increased from 240 to 550 kA/m as the magnetic field raised from 0.01 to 0.75 T. These results are promising and significant for further investigations of the mechanisms underlying the formation of PMA. Thus, our developed PLD facility for in-situ PNR measurements demonstrates unique capabilities for growing thin-film structures of varying complexity and investigating them directly at the neutron beamline.

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Conflicts of Interest

The authors declare no conflict of interest.

Authors Contribution

Project administration, Supervision, Funding acquisition and Investigation, K.M. and A.Goikhman.; Resources, A.V. and A. Devishvilli; Conceptualization, A.Dolgoborodov and P.P.; Investigation, A.Grunin; Investigation, Formal analysis, Visualization, Writing – original draft, G.K.; Writing – review & editing, P.S.

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b)





Neutron window (reflected beam)



Type K mini plug + power feedthrough

Neutron window (incident beam)

Nd:YAG laser window

Target viewport





Sample in the centre



Shifted sample

Nd:YAG Pulsed Laser

Sample

A

unit

Spin-flipper

Diaphragm

Sample shutter

Type K mini plug + power feedthrough

I Vacuum gauge

Analyser

